Hydrogen Peroxide, 30% CMOS (Stabilized)





Material No.: 2190-23 Batch No.: 0000089316 Manufactured Date: 2014/08/29

Expiration Date: 2016/02/27

Certificate of Analysis

Test	Specification	Result
Assay (H ₂ O ₂)	30.0 - 32.0 %	31.2
Color (APHA)	<= 10	5
Free Acid (µeq/g)	<= 0.2	< 0.2
Residue after Evaporation	<= 10 ppm	< 5
Ammonium (NH ₄)	<= 3 ppm	< 3
Chloride (CI)	<= 0.2 ppm	< 0.2
Nitrate (NO ₃)	<= 2 ppm	< 2
Phosphate (PO ₄)	<= 1 ppm	< 1
Sulfate (SO ₄)	<= 3 ppm	< 3
Trace Impurities – Aluminum (Al)	<= 70.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities - Barium (Ba)	<= 20.0 ppb	< 1.0
Trace Impurities – Beryllium (Be)	<= 10.0 ppb	< 1.0
Trace Impurities – Bismuth (Bi)	<= 20.0 ppb	< 10.0
Trace Impurities – Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities – Cadmium (Cd)	<= 10.0 ppb	< 1.0
Trace Impurities - Calcium (Ca)	<= 50.0 ppb	< 1.0
Trace Impurities - Chromium (Cr)	<= 20.0 ppb	< 1.0
Trace Impurities - Cobalt (Co)	<= 10.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities - Gallium (Ga)	<= 20.0 ppb	< 1.0
Trace Impurities - Germanium (Ge)	<= 10.0 ppb	< 10.0
Trace Impurities - Gold (Au)	<= 10.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 500 ppb	< 250

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Trace Impurities - Iron (Fe)	<= 50.0 ppb	< 1.0
Trace Impurities - Lead (Pb)	<= 10.0 ppb	< 10.0
Trace Impurities - Lithium (Li)	<= 10.0 ppb	< 1.0
Trace Impurities - Magnesium (Mg)	<= 10.0 ppb	< 1.0
Trace Impurities - Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities - Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities - Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities - Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 600.0 ppb	247.0
Trace Impurities – Silicon (Si)	<= 100.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities – Thallium (Tl)	<= 50.0 ppb	< 5.0
Trace Impurities – Tin (Sn)	190.0 - 500.0 ppb	351.8
Trace Impurities – Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities – Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 10.0 ppb	< 1.0
Particle Count – 0.5 µm and greater	<= 100 par/ml	6
Particle Count - 1.0 µm and greater	<= 10 par/ml	1

For Microelectronic Use

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004
Paris, KY 9001:2008
Mexico City, Mexico 9001:2008
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
Gliwice, Poland 9001:2008, 17025:2005
Selangor, Malaysia 9001:2008
Dehradun, India, 9001:2008, 14001:2004, 13485:2003
Mumbai, India, 9001:2008, 17025:2005
Panoli, India 9001:2008

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